

# Gaussian Process Emulators for Expensive Simulations

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Oberseminar

December 13, 2018



1. Expensive functions
2. Gaussian process emulators
3. Applications to Bayesian inverse problems (BIP)
4. Sequential design for Gaussian process emulators in BIP

Expensive functions

## Example: Bayesian optimisation

- ★ Say we are interested in

$$x^* = \arg \min_{x \in D} F(x)$$

- ★ First problem:  $F$  is **really** expensive to evaluate
- ★ Second problem: We do not know anything about  $F$
- ★ (except Lipschitz continuity, maybe)
- ★ This is the general framework of **Bayesian optimisation**

## Example: Mean of probability distribution

- ★ Let  $f : A \rightarrow \mathbb{R}$  the density of a probability measure
- ★ Problem:  $f$  is **really** expensive to evaluate
- ★ What if we need the expected value

$$\mathbb{E}_\mu[X] = \int x f(x) dx \approx \frac{1}{N} \sum_{i=1}^N x_i f(x_i)$$

- ★ This problem is common in Bayesian inverse problems

## Gaussian process emulators

- ★ Say  $X = \{x_1, \dots, x_N\}$  is a set of locations
- ★ Reconstruct  $f$  from noisy data  $y = f(X) + \eta$ ,  $\eta \sim \mathcal{N}(0, \sigma^2)$
- ★ Assume that  $f$  is a realisation of a **Gaussian process**

## Definition (Gaussian process)

A Gaussian process  $Z_f$  is a random field, for which any finite number of evaluations has multivariate Gaussian distribution.

- ★ Write:  $Z_f \sim \text{GP}(m, K) = \text{GP}(m(\cdot), K(\cdot, \cdot))$
- ★  $K$  is symmetric and positive definite

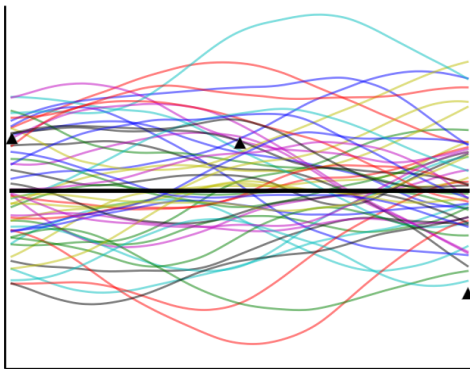
## Reconstruction problem



Data points; which function do these data points come from?



## Sample paths of a Gaussian process



Data points and sample paths of a Gaussian process

## Conditioning Gaussian processes

- ★ Assume we want to reproduce  $Z_f \sim \text{GP}(m, K)$  at a point  $s$
- ★ Joint distribution:

$$\begin{pmatrix} Z_f(X) \\ Z_f(s) \end{pmatrix} \sim \mathcal{N} \left( \begin{pmatrix} m(X) \\ m(s) \end{pmatrix}, \begin{pmatrix} K(X, X) + \sigma^2 I_N & K(X, s) \\ K(s, X) & K(s, s) \end{pmatrix} \right)$$

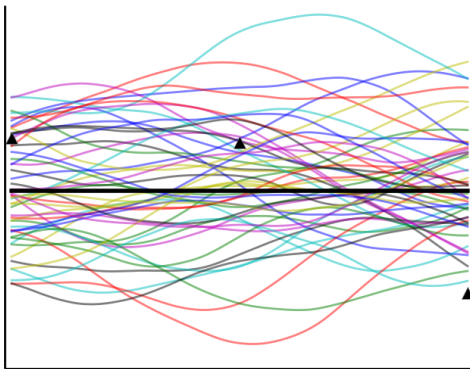
$$\Rightarrow Z_f(s) |_{Z_f(X)+\eta=y} \sim \mathcal{N}(\hat{m}(s), \hat{K}(s, s)),$$

with predictive mean and predictive covariance

$$\hat{m}(s) := m(s) - K(s, X)(K(X, X) + \sigma^2 I_N)^{-1}(m(s) - y)$$

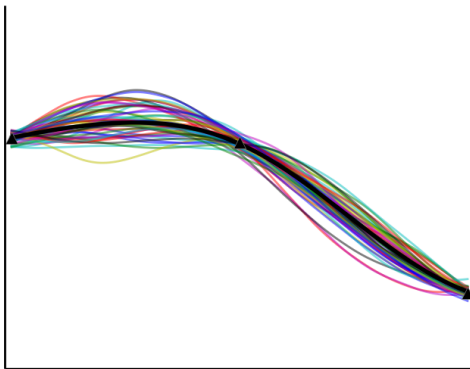
$$\hat{K}(s, t) := K(s, t) - K(s, X)(K(X, X) + \sigma^2 I_N)^{-1}K(X, t)$$

## Sample paths of a Gaussian process



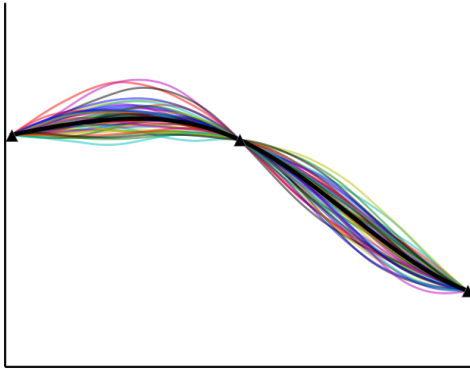
Data points and sample paths of a Gaussian process

## Sample paths of a conditioned Gaussian process



Sample paths of a conditioned Gaussian process

## Sample paths for exact data (i.e., $\sigma^2 = 0$ )



Sample paths of a conditioned Gaussian process with exact data

Applications to Bayesian inverse problems (BIP)

## Differential Equation on $(0, 1)$

Find  $a = (a_1, a_2) \in [-1, 1]^2$  such that for

$$-\operatorname{div}((\sin(a_1 x) + \cos(a_2 x)) \nabla u(x)) = 1, \quad u(0) = u(1) = 0$$

the measurements  $y = (u(1/3), u(1/2), u(2/3))$  satisfy

$$u(1/3) = 2.2514, \quad u(1/2) = 6.213, \quad u(2/3) = 0.526.$$

- ★ Say  $\mathcal{G} : [-1, 1]^2 \rightarrow \mathbb{R}^3$ ,  $(a_1, a_2) \mapsto (u_a(1/3), u_a(1/2), u_a(2/3))$
- ★ Problem: Find  $a \in [-1, 1]^2$  from  $y = \mathcal{G}(a) + \epsilon$ ,  $\epsilon \sim \mathcal{N}(0, \sigma_\epsilon^2)$

## Bayesian inverse problems

- ★ Initial belief of parameters: **prior distribution**  $\mu_0$  on  $[-1, 1]^2$
- ★ Improve prior distribution: **posterior distribution**  $\mu^y$ 
  - ★ using observations  $y$  (think:  $y = (2.2514, 6.213, 0.526)$ )
  - ★ using forward map  $\mathcal{G}$  (remember: **expensive**)
- ★ Posterior distribution can be written as

$$\mu^y(x) \propto L(x)\mu_0(x)$$

- ★  $L(x) = L(x|y, \mathcal{G})$  is called **likelihood**



- ★ Evaluations of the likelihood need evaluations of  $\mathcal{G}$
- ★ This is expensive!
- ★ Solution: Emulate the likelihood with a Gaussian process!
- ★ This works because small errors in the likelihood imply small errors in the posterior



A. M. Stuart, A. L. Teckentrup.

*Posterior Consistency for Gaussian Process Approximations of Bayesian Posterior Distributions.*

Math. Comp. 87, 721-753, 2018

# Sequential design for Gaussian process emulators in BIP

## Challenges:

- ★ Posterior measure concentrates w.r.t. prior
- ★ Capture this concentration in the locations for the emulator
- ★ We do not know the concentration a-priori

## Strategy:

- ★ Abstract point of view:  $\nu_N := \text{GP}(m_N, K_N)$  approx. on  $N$  pts
- ★ Choose one location after the other:  $\nu_N \rightarrow \nu_{N+1}$
- ★ Minimise the expected risk using the information  $\nu_N$

## A promising strategy: Bayesian risk minimisation

Pick the new node as

$$x_{N+1} = \arg \min_x \mathbb{E}_{\mu_0} \left[ \mathbb{E}_{\gamma_N(x)} \left[ \mathbb{V}_{\nu_{N+1}(x)} \left[ L(\cdot | \mu_0) | y, \cdot | \nu_{N+1}(x) \right) \right] \right] \right],$$

where

- ★  $\mu_0$  is the prior distribution in the inverse problem
- ★  $\gamma_N(x)$  is the law of the current GP  $\nu_N$  at candidate point  $x$
- ★  $\nu_{N+1}(x)$  is the law of the next GP if one picks  $x$  as a new node






M. Sinsbeck, W. Nowak.

*Sequential Design of Computer Experiments for the Solution of Bayesian Inverse Problems.*

SIAM/ASA J. Uncertainty Quantification 5(1), 640-664, 2017

- ★ Check whether the sequential design strategy delivers:
  - ★ Reproduce the experiments
  - ★ Find a way to make it fail?
- ★ Check different variations
- ★ Compare to other experimental design algorithms
- ★ *Think about why this works?*

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-  M. Sinsbeck.  
*Uncertainty Quantification for Expensive Simulations—Optimal Surrogate Modeling under Timer Constraints.*  
Dissertation, Universität Stuttgart, 2017